First workshop on Hard X-ray Micro/Nano probe at PETRA III

Tuesday 22 January 2008

Session on third generation SR applications I - 109, bldg. 25b (11:00 - 12:30)

time	[id] title	presenter
11:00	[3] Analysing materials at different length scales	JANSSENS, Koen
11:30	[4] Non-destructive 3-dimensional synchrotron-XRF trace element measurements of down to the nanoscale	BRENKER, Frank
12:00	[19] Probing biomedical tissues - a challenge for analysis and sample preparation	SCHROEDER, Walter